Se	arcn	<i>Note</i> :	5

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/780,793	LEE, BEN	
Examiner	Art Unit	
Yogesh K. Aggarwal	2622	

SEARCHED			
Class	Subclass ,	Date	Examiner

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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
348/222.1,207.99,373- 376,151,157,158,143,386/46,117,52,3 58/906,909.1,396/422,423,428,d16/24 2,2/94,101	8/3/2007	YKA
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